# Development of a Novel Bismuth Precursor for MOCVD

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# 1 . Introduction

Bismuth layer-structured ferroelectrics (BLSF) have been investigated as the capacitor materials of next generation memory devices including ferroelectric random access memories (FeRAMs)<sup>1)-3)</sup>. BLSF are attractive materials for FeRAMs because they show excellent fatigue endurance.

For the realization of highly integrated devices, more attentions come to be paid to metalorganic chemical vapor deposition (MOCVD). MOCVD is indispensable technique for three-dimensional structure memory devices because of its good step coverage and high growth rate.

There have been several reports on BLSF films preparation by MOCVD using several bismuth precursors, for example  $BiMe_3$ , triarylbismuth  $[BiPh_3$ and  $Bi(0 \cdot Tol)_3$ ] and trialkoxidebismuth  $[Bi(O^tBu)_3$  and  $Bi(mmp)_3$ ]. Among these bismuth precursors, only  $BiMe_3$  is a liquid at room temperature. Liquid precursors are of great advantage for MOCVD process from the viewpoint of the material delivery system. However,  $BiMe_3$  is explosive. It is not safe to handle  $BiMe_3$ , especially under mass production process at the factories.

On the other hand triarylbismuth and trialkoxidebismuth are under great disadvantage to MOCVD from the viewpoint of the source delivery system because they are solid and don t have high vapor pressure.

In this work, a development of a novel liquid bismuth precursor for MOCVD is developed that can be use safety and has high vapor pressure.

# 2 . Experiment

The molecular structure of BiMe<sub>2</sub>(Me<sub>2</sub>NCH<sub>2</sub>Ph) is shown in Fig.1 and is synthesized from bismuth halides, methylating agents and arylating agents.

### 2.1 Preparation

Diethylether was purified by distillation from sodium / benzophenone under argon. All other solvents were deoxidized by bubbling argon before use. Nuclear magnetic resonance (NMR) spectra were measured with a Varian VXR.500s spectrometer. Mass spectra were determined on mass spectrometry (MS) using an Applied Biosystems QTRAP at TOSOH Analysis and Research Center.

Dimethyl(2 · (N, N · dimethylaminomethylphenyl) bismuth · Methylmagnesiumbromide solution (0.6M 25ml, 15.0mmol) in diethylether was added dropwise to a suspension of dicholo(2 · (N, N · dimethylaminomethyl · phenyl)bismuth (3.30g, 8.0mmol), prepared from bismuth chloride and 2 · (N, N · dimethylaminomethylphenyl)lithium, and diethylether at ·78 under argon. After the addition was complete, the reaction mixture was allowed to warm to room temperature (R.T.) and stirred for 20h. After the reaction, the reaction mixture was quenched with aqueous NH<sub>4</sub>Cl, and extracted with diethylether. The extract was concentrated *in vacuo* and distillation of the residue gave light yellow oil (1.42g, 48%).

<sup>1</sup>H-NMR (500 MHz, CDCl<sub>3</sub>, /ppm): 7.95 (d, J=7.0 Hz, 1H, ArH), 7.22 (m, 2H, ArH), 7.15 (d,J=7.0 Hz, 1H, ArH), 3.45 (s, 2H, CH<sub>2</sub>),2.17 (s, 6H, NMe), 1.06 (s, 6H, Me). <sup>13</sup>C-NMR (CDCl<sub>3</sub>, /ppm): 177.53 (s, C), 144.53 (s, C), 137.07 (s, CH), 128.60 (s, CH), 128.57 (s, CH), 126.90 (s, CH), 67.66 (s, CH<sub>2</sub>), 44.80 (s, CH<sub>3</sub>), 3.08 (s,

CH<sub>3</sub>). MS: m/z = 374 (M<sup>+</sup>+H). Elemental analysis: C (35.6%), H (5.0%), N (3.7%), Bi (53.5%). C<sub>11</sub>H<sub>18</sub>BiN requires C (35.4%), H (4.9%), N (3.8%), Bi (56.0%).

#### 2.2 Measurement of physical properties

Viscosity was measured by use of a rotational viscometer. Vapor pressure was measured directly under high reduced pressure in a closed system using an absolute capacitance manometer. Volatility of Bi precursors was estimated by thermo-gravimetry analysis (TG) and decomposition temperature was measured using a differential scanning calorimeter (DSC).

## 2.3 Films preparation by MOCVD

 $Bi_4Ti_3O_{12}$  were prepared by MOCVD using BiMe<sub>2</sub>(Me<sub>2</sub>NCH<sub>2</sub>Ph), Ti(O<sup>i</sup>C<sub>3</sub>H<sub>7</sub>)<sub>4</sub> and O<sub>2</sub> gas. Film composition was calculated and decided by X-ray fluorescence spectroscopy (XRF), which was calibrated with standard film samples. Constituent phases and orientation of the films were characterized by X-ray diffraction (XRD) using CuK radiation. Film thickness was measured by field-emission scanning electron microscopy (FE-SEM).



Fig. 1 Molecular structure of BiMe<sub>2</sub>(Me<sub>2</sub>NCH<sub>2</sub>Ph)

#### 3 . Results and Discussion

A novel bismuth precursor, BiMe<sub>2</sub>(Me<sub>2</sub>NCH<sub>2</sub>Ph) was synthesized successfully from bismuth chloride as starting compound and characterized by <sup>1</sup>H·NMR and <sup>13</sup>C·NMR.

Physical properties of  $BiMe_2(Me_2NCH_2Ph)$  is shown in Table 1.  $BiMe_2(Me_2NCH_2Ph)$  melts at  $\cdot$ 49 and is a light yellow liquid of low viscosity (ca.7 cP) at ambient temperature .Furthermore, it has high vapor pressure (0.1Torr/55 ) as MOCVD precursor. From the view point of precursor delivery, liquid phase at room temperature provides great advantage as MOCVD precursor.

The flash point of BiMe<sub>2</sub>(Me<sub>2</sub>NCH<sub>2</sub>Ph) is 148 and it is a nonexplosive compound. The gradually oxidative decomposition of BiMe<sub>2</sub>(Me<sub>2</sub>NCH<sub>2</sub>Ph) occurs in contact with O2 gas, while the reactivity of BiMe<sub>2</sub>(Me<sub>2</sub>NCH<sub>2</sub>Ph) with H<sub>2</sub>O is hardly observed. In case of mixing BiMe<sub>2</sub>(Me<sub>2</sub>NCH<sub>2</sub>Ph) and popular other metal precursor, that is  $Sr(C_{11}H_{19}O_2)_3$ ,  $La(C_{11}H_{19}O_2)_3$ ,  $Sr[Ta(OC_2H_5)_2(OC_2H_4OCH_3)]_2$  $Ta(OC_2H_5)_5$  $Ti(O^{i}C_{3}H_{7})_{4}$  or  $Ti(O^{i}C_{3}H_{7})_{2}(C_{11}H_{19}O_{2})_{2}$  directly or dissolved in benzene at R.T., no chemical change in the mixture was observed. As films preparation by MOCVD, BiMe<sub>2</sub>(Me<sub>2</sub>NCH<sub>2</sub>Ph) can be use safety and without its decomposition by such as popular precursor listed above.

Table 1	Physical	properties	of	BiMe <sub>2</sub>	(Me <sub>2</sub> NCH <sub>2</sub> Ph	)
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vapor pressure	0.1 Torr/55		
decomposition temprature	230		
melting point	- 49		
flash point	148		
viscosity	7cP		
reactivity with H <sub>2</sub> O	less reactive		
reactivity with O <sub>2</sub>	gradually reactive		

Fig.2 shows the TG curves as a function of temperature.  $BiMe_2(Me_2NCH_2Ph)$  is more volatile than  $BiPh_3$  because molecular weight of  $BiMe_2(Me_2NCH_2Ph)(Mw373.3)$  is smaller than that of  $BiPh_3(Mw440.3)$ .



Fig. 2 TG curves of (a)  $BiMe_2(Me_2NCH_2Ph)$  and (b) BiPh<sub>3</sub> under Ar atmosphere (heating rate 10 /min)

Fig.3 shows the TG curves and the DSC curves as a function of temperature. The exothermic peaks indicate the decomposition temperatures of the precursors. The result shows that the starting temperature of decomposition of  $BiMe_2(Me_2NCH_2Ph)$  is 230 and  $BiMe_2(Me_2NCH_2Ph)$  can be vaporized before thermal decomposition. In other words, vaporized  $BiMe_2(Me_2NCH_2Ph)$  can be supplied by MOCVD without thermal decomposition.



Fig. 3 TG curve and DSC curve of BiMe<sub>2</sub>(Me<sub>2</sub>NCH<sub>2</sub>Ph) under inert gas atmosphere (heating rate 10 / min)

In respect with molecular structure of BiMe<sub>2</sub>(Me<sub>2</sub>NCH<sub>2</sub>Ph), it is assumed that BiMe<sub>2</sub>(Me<sub>2</sub>NCH<sub>2</sub>Ph) has the intramolecular Bi·N coodinate bond by the results of X-ray structure analysis of similar structures, Bi(m. Tol)<sub>2</sub>(Me<sub>2</sub>NCH<sub>2</sub>Ph), to BiMe<sub>2</sub>(Me<sub>2</sub>NCH<sub>2</sub>Ph). Fig.4 shows the result of X-ray structure analysis of Bi(m- $Tol)_2(Me_2NCH_2Ph)$  and the Bi  $\cdot$  N length of it is 2.94 .

The intramolecular  $Bi \cdot N$  coodinate bond of  $BiMe_2(Me_2NCH_2Ph)$  prevent  $BiMe_2(Me_2NCH_2Ph)$  from disproportionation of ligands and explosive decomposition.

Fig.5 shows the XRD -2 scans of the asdeposited BIT(Bi<sub>4</sub>Ti<sub>3</sub>O<sub>12</sub>) film with 150nm in thickness prepared on (111)Pt/Si substrate at 500 by MOCVD using BiMe<sub>2</sub>(Me<sub>2</sub>NCH<sub>2</sub>Ph), Ti(O<sup>i</sup>C<sub>3</sub>H<sub>7</sub>)<sub>4</sub> and O<sub>2</sub> gas as starting materials. (00*I*) and (117) diffraction peaks of BIT phase were detected together with that of Pt phase. N atom did not be found from the BIT film by XPS analysis. In other words, the N atoms that are the included element in BiMe<sub>2</sub>(Me<sub>2</sub>NCH<sub>2</sub>Ph) did not largely incorporated into the films during its



Fig. 4 A drawing of X-ray structure of single crystal of Bi(m-Tol)<sub>2</sub>(Me<sub>2</sub>NCH<sub>2</sub>Ph)



Fig. 5 XRD -2 scans of the BIT films prpared by MOCVD from BiMe<sub>2</sub>(Me<sub>2</sub>NCH<sub>2</sub>Ph)-Ti(O<sup>1</sup>C<sub>3</sub>H<sub>7</sub>)<sub>4</sub>-O<sub>2</sub> systems

decomposition.

Other bismuth-contained oxide films, for example  $SrBi_2Ta_2O_9^{4}$ ,  $Bi_2Zn_XNb_{1-X}O_7^{5}$  and  $BiFeO_3^{6}$ , can be also prepared by MOCVD using  $BiMe_2(Me_2NCH_2Ph)$  as a starting bismuth precursor.

## 4 . Conclusion

In this work, we have synthesized a novel Bi precursor  $BiMe_2(Me_2NCH_2Ph)$  for MOCVD and its physical properties were examined. This compound is nonexplosive, liquid at ambient temperature and showed excellent volatility and adequate decomposition

temperature. As the MOCVD source for films preparation, BLSF and other bismuth-contained oxide films can be prepared by MOCVD using BiMe<sub>2</sub>(Me<sub>2</sub>NCH<sub>2</sub>Ph).

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